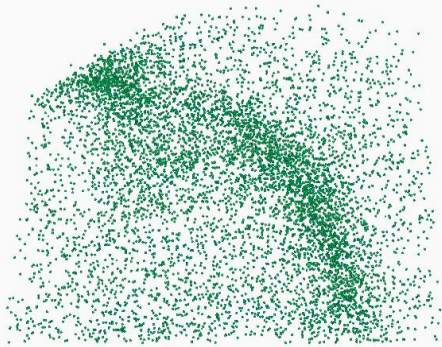


# Transport along grain boundaries through alumina investigated by atom probe tomography

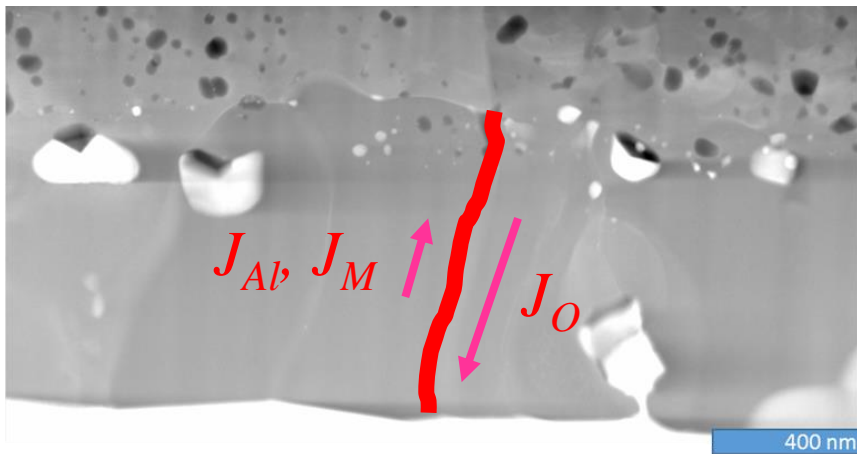
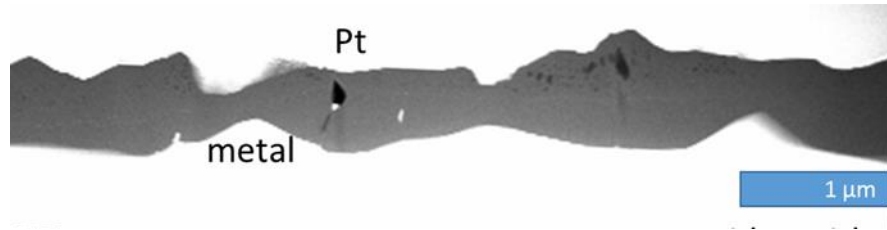
Torben Boll\*, Kinga A. Unocic, Bruce A. Pint, Krystyna Stiller

20 nm



Atom Probe Tomography:  
Zr at a grain boundary in  $\text{Al}_2\text{O}_3$ ,  
Each dot represents one atom,  
Al and O atoms are not displayed

# TEM of typical oxide on NiAl

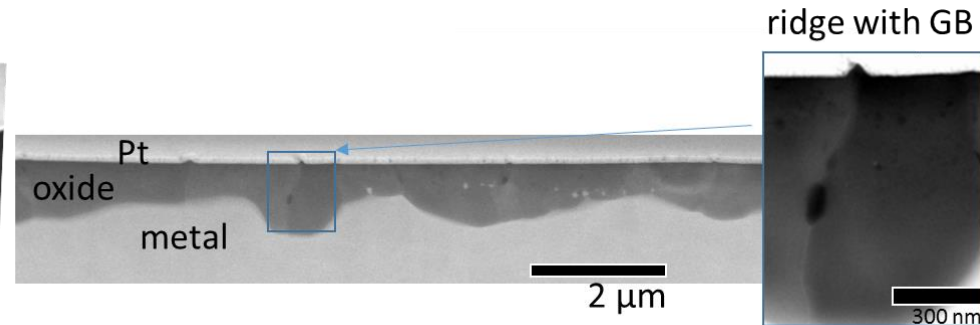
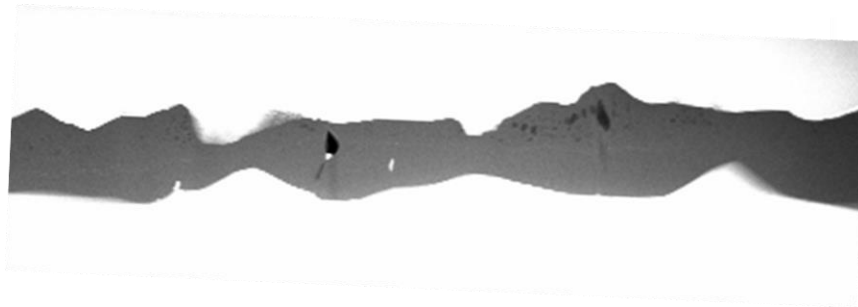
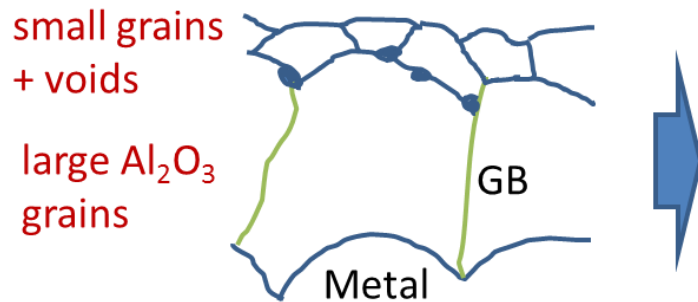


- Protective Al<sub>2</sub>O<sub>3</sub> coating on NiAl-alloy
- O (and all other elements) in α-alumina diffuse mostly via grain boundaries (GBs)
- Minor outward diffusion of metal
- Decoration of GBs will influence the diffusion and thus oxidation
- Apparently grows inwards

Material	Ni at.%	Al at.%	Zr ppma	Hf ppma	N ppma	C ppma	Sxx ppma	O ppma	B ppma	Cr ppma
Zr-doped	49.95	49.99	520	0	0	0	3	48	30	0
Hf-doped	49.83	50.07	0	480	30	36	0	43	0	100

# Outward diffusion: Exp. idea

a) After 1<sup>st</sup> exposure



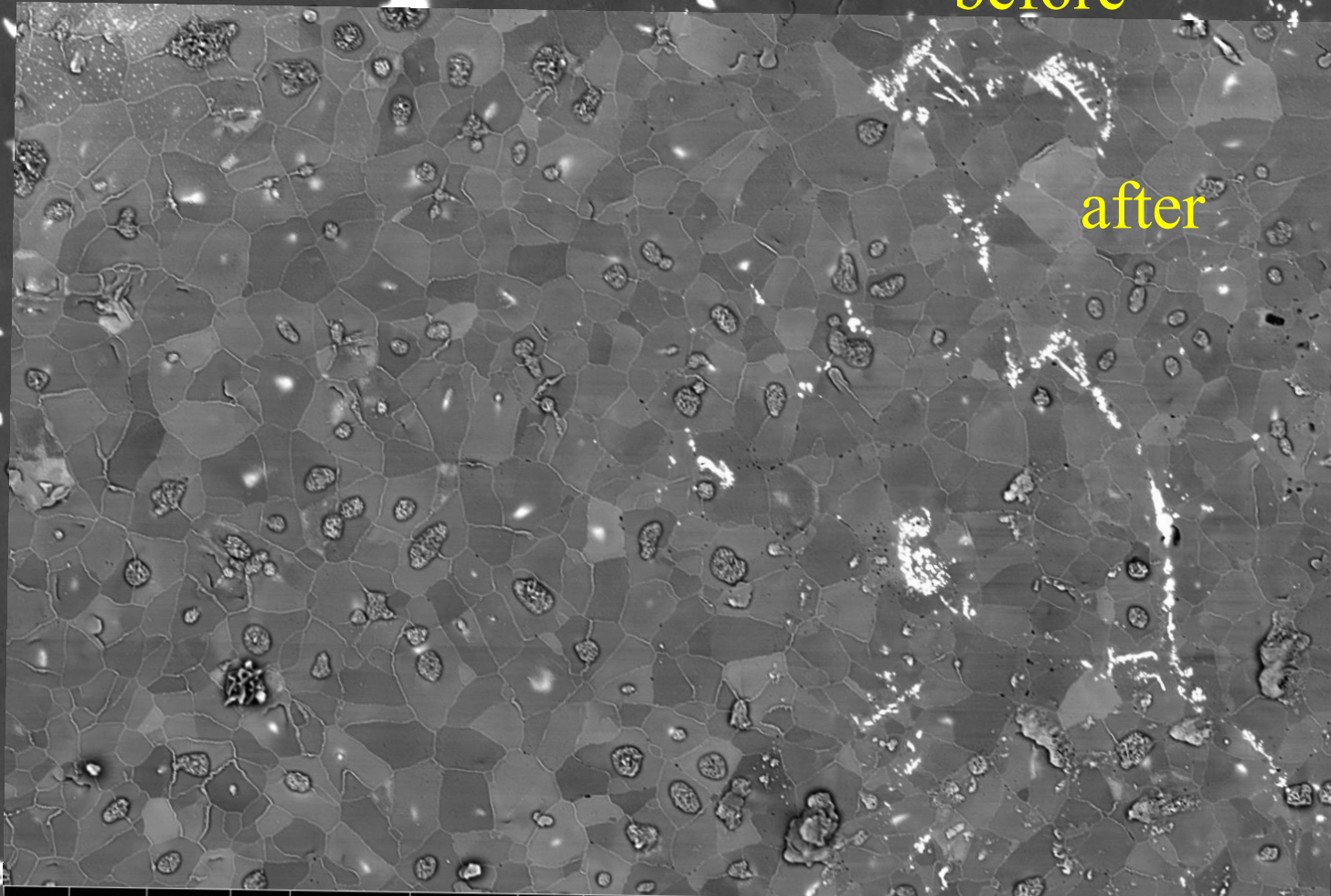
[1] V. K. Tolpygo and D. R. Clarke, *Mater. High Temp.*, vol. 20, no. 3, pp. 261–271, 2003


[2] J. a. Nychka and D. R. Clarke, *Oxid. Met.*, vol. 63, no. 5–6, pp. 325–352, 2005

# Hf 10h exposure

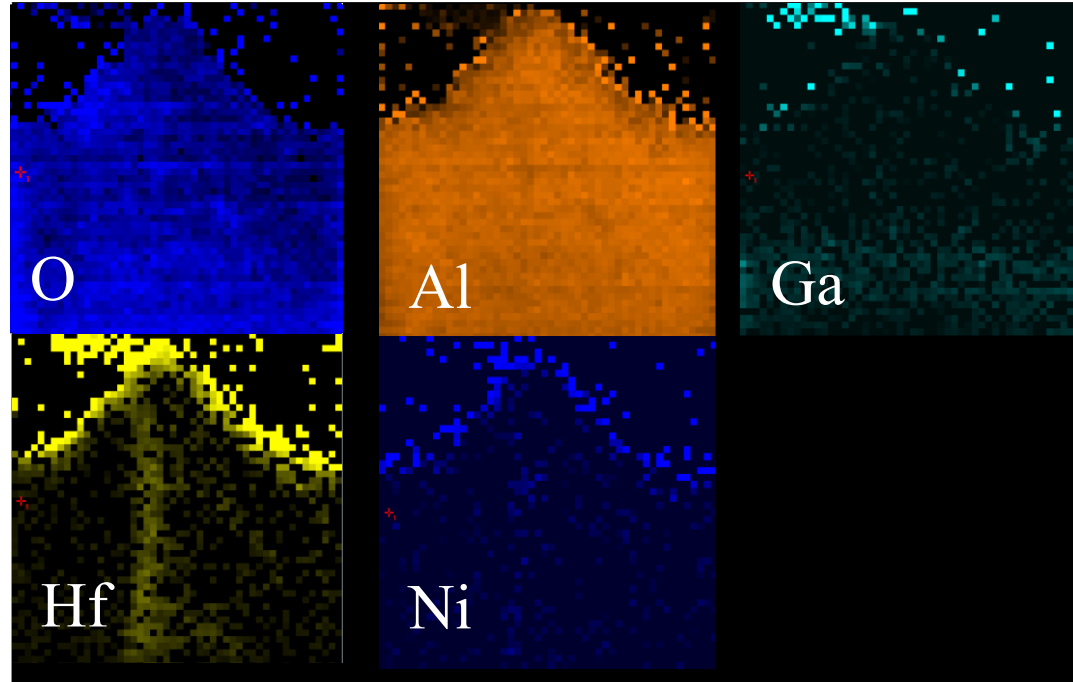
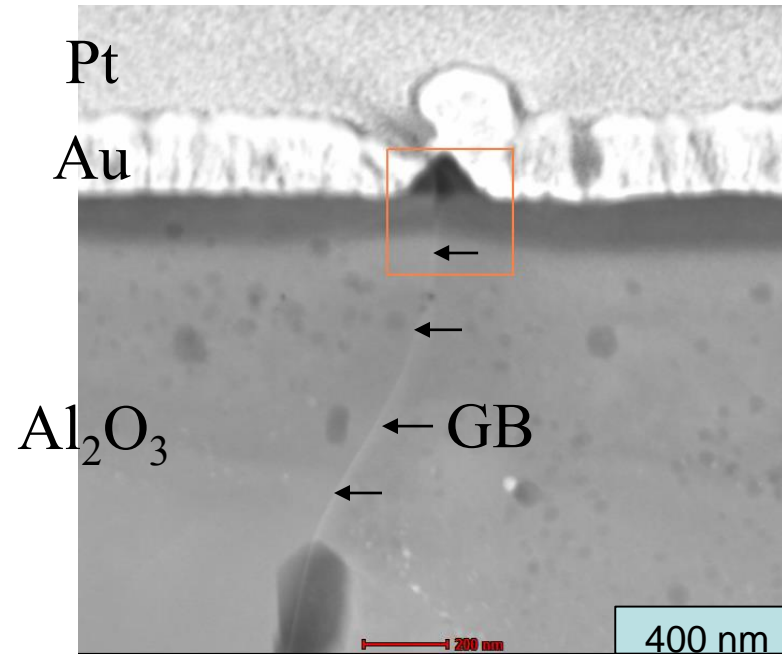
before

after



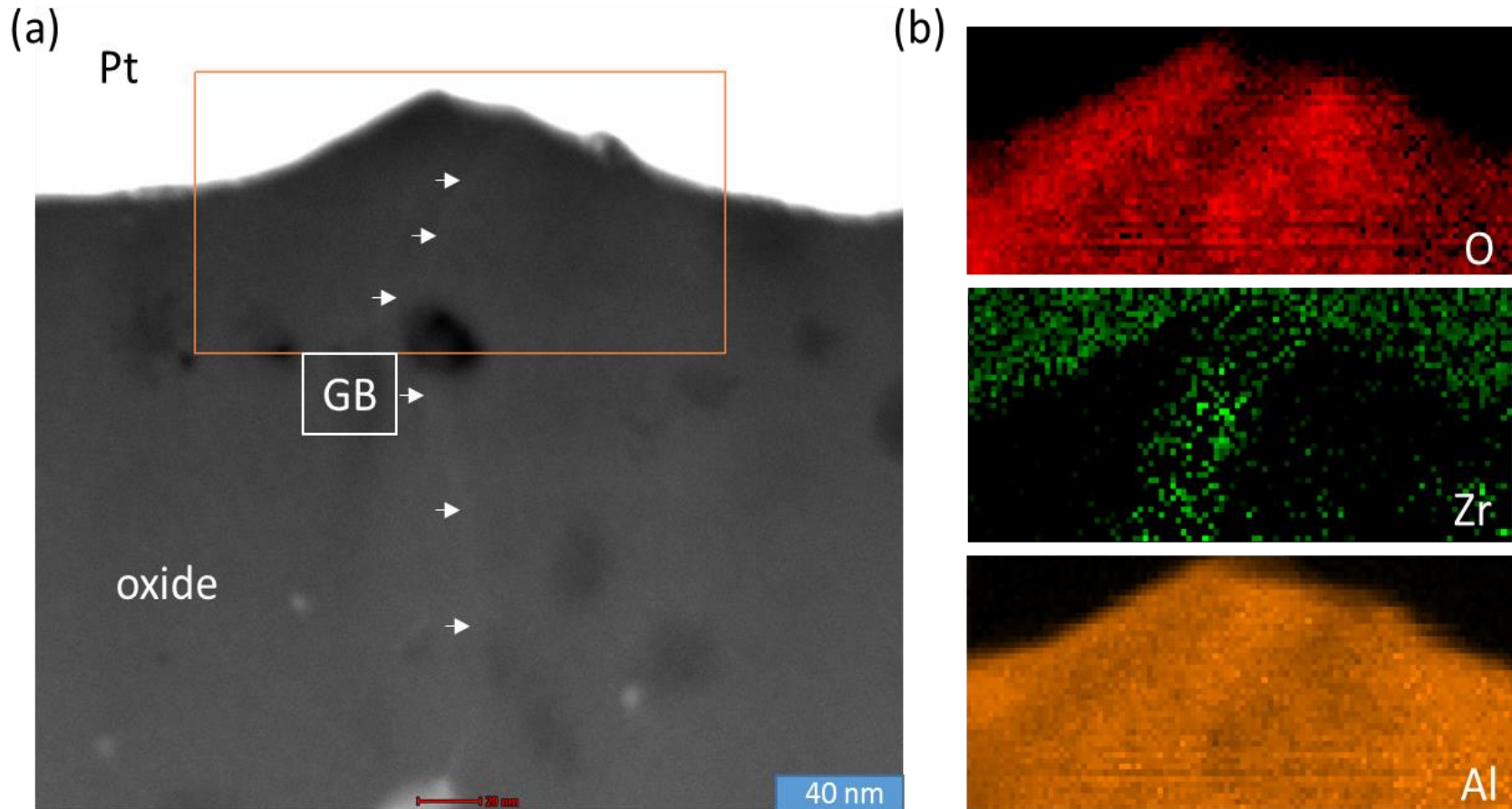
	mode	dwell	tilt	WD	HV	spot	30 $\mu\text{m}$	
	All	60 $\mu\text{s}$	0 $^\circ$	10.1 mm	5.00 kV	1.0		

# TEM of mech. pol. Hf sample



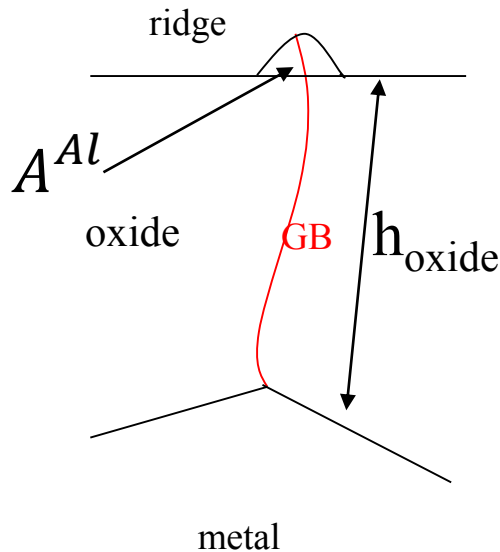
- No Ga contamination
- GB enriched with Hf and some Ni

# TEM of Zr sample



- Zr enriched at the GB

# How to calculate the flux



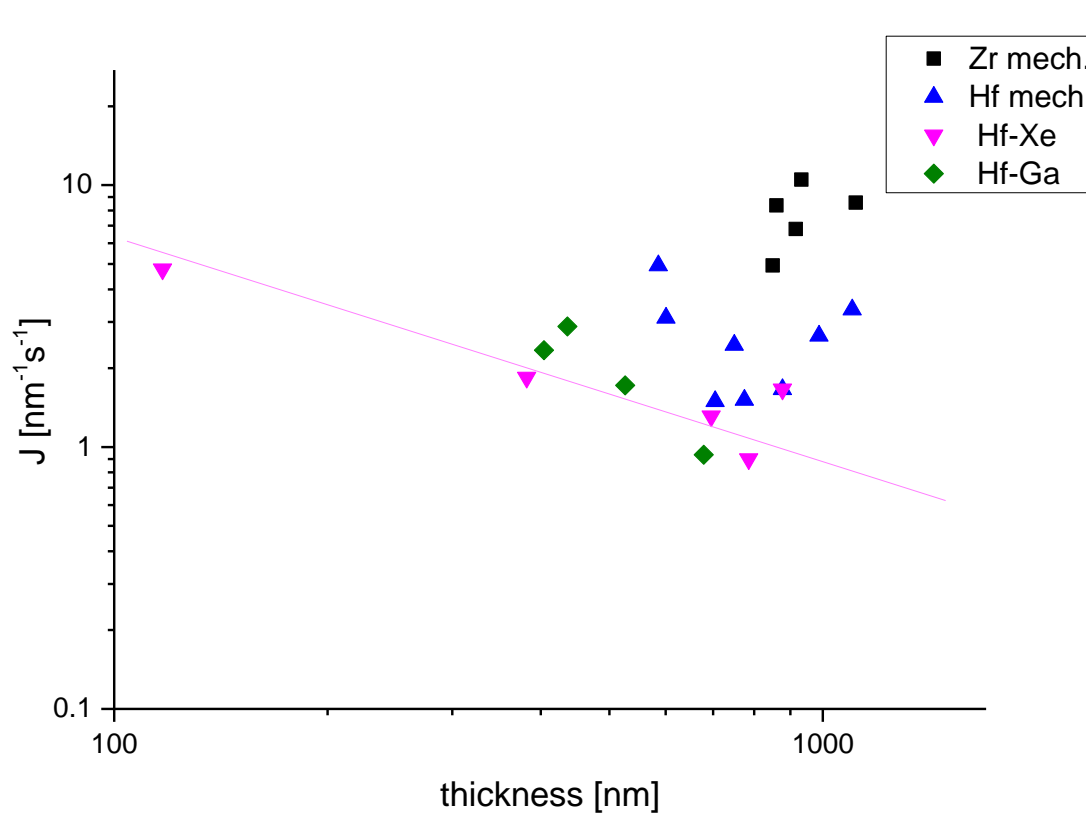
- Calculate the flux
  - Number of diffused Al-atoms  $N_{GB}^{Al}$
  - Exposure time  $\Delta t$  (10h)
- Calculate number of atoms
  - Volume of ridge  $V^{Al} = A^{Al} L_{GB}$
  - Length of GB  $L_{GB}$  (not height!)
  - Cross section area of ridge  $A^{Al}$
  - Volume of  $Al_2O_3$  unit cell:  $V_u = 2.54 \cdot 10^{-22} \text{ cm}^3$
  - Number of Al atoms per unit cell: 12

$$J_{Al} = \frac{N_{GB}^{Al}}{L_{GB} \Delta t}$$

$$N_{GB}^{Al} = \frac{12 V^{Al}}{V_u}$$

$$J_{Al} = \frac{12 A^{Al}}{V_u}$$

# Flux of Al through GBs at 1100°



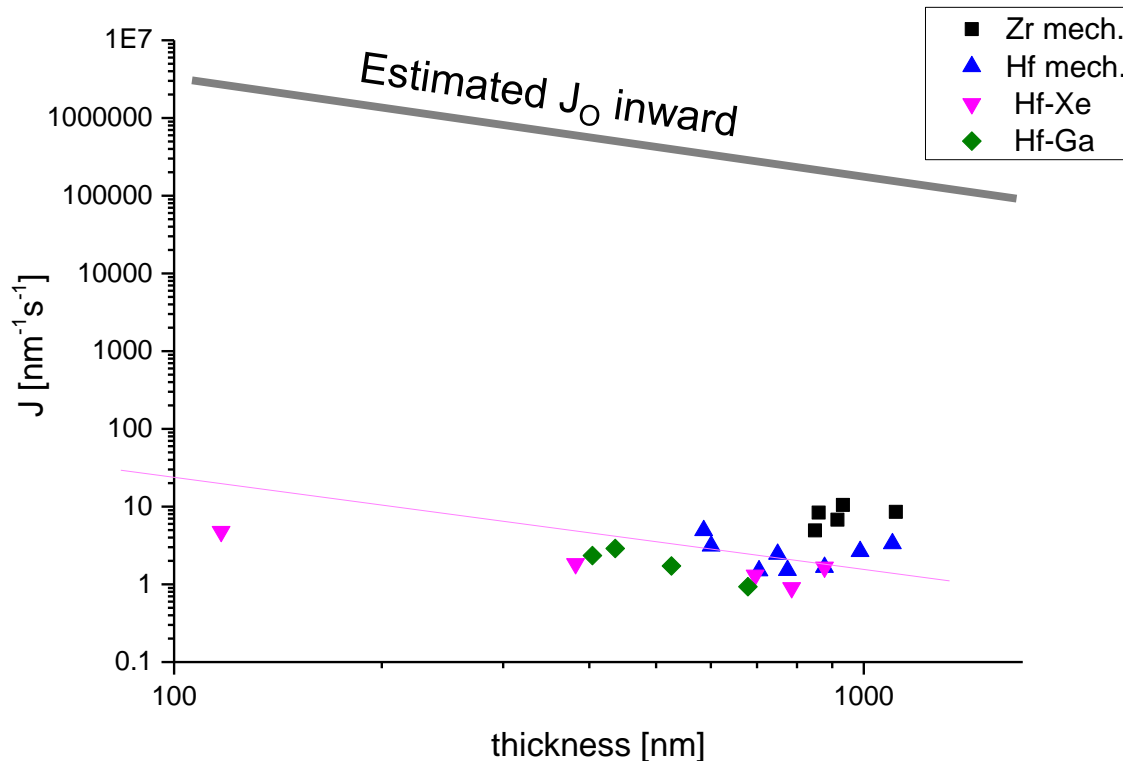
- Mech. polishing enhances ridge growth
- Zr allows higher outward flux than Hf

Should follow Fick's 1. law  
(assuming  $h_{\text{oxide}}$  is constant)

$$J_{\text{GB}}^{\text{Al}} = -\frac{A}{h_{\text{oxide}}}$$



# Flux of Al through GBs at 1100°

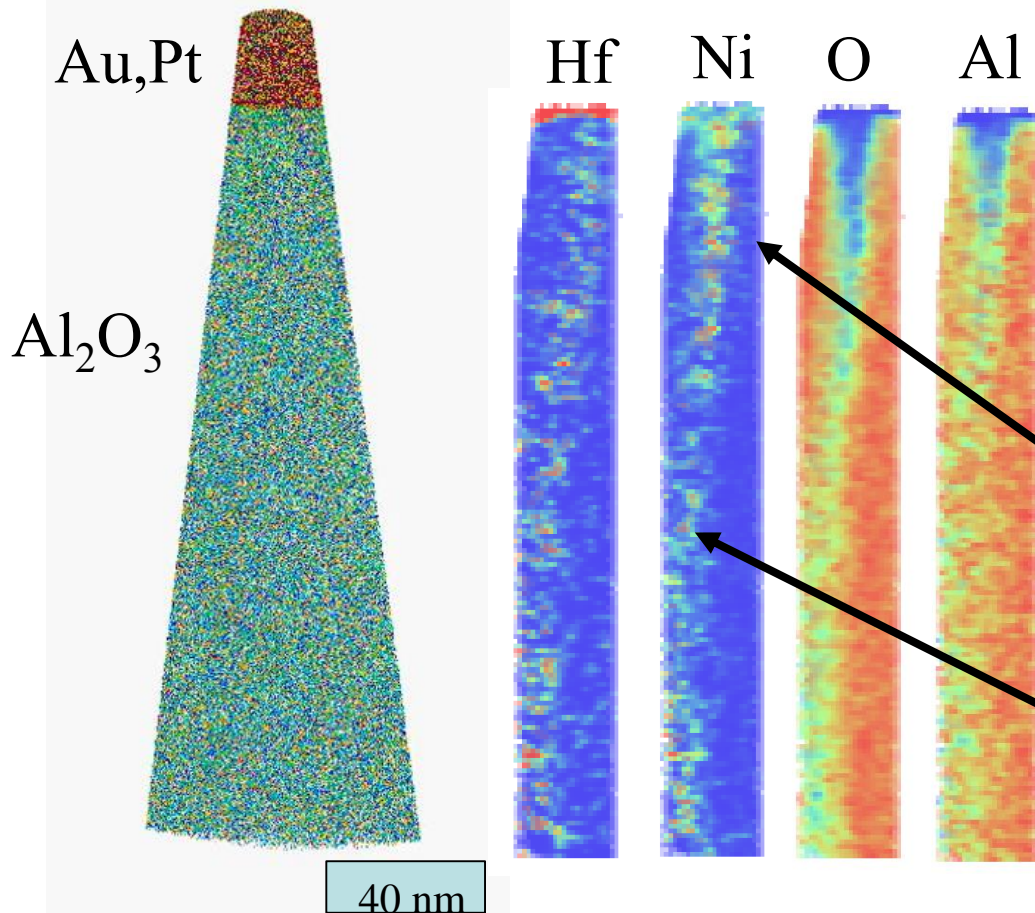


- Mech. polishing enhances ridge growth
- Zr allows higher outward flux than Hf
- Inward flux six orders of magnitude larger

Should follow Fick's 1. law  
(assuming  $h_{\text{oxide}}$  is constant)

$$J_{\text{GB}}^{\text{Al}} = -\frac{A}{h_{\text{oxide}}}$$

# APT of Hf sample

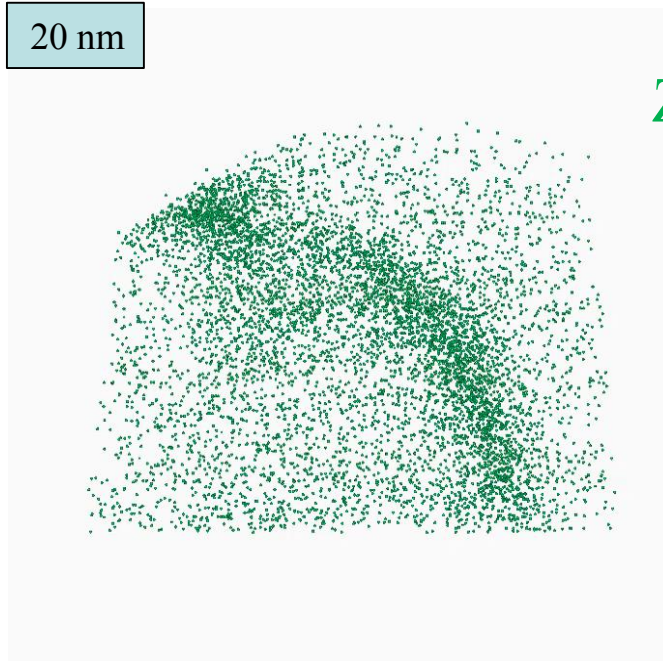


- Protective Au,Pt coating
- GB with Hf, Ni
- Ni enriched at surface
- Gibbsian excess  $\Gamma$   
(Number of additional atoms per area in GB):

Hf:  $0.5 \text{ nm}^{-2}$   
Ni:  $2.6 \text{ nm}^{-2}$

Hf:  $0.35 \text{ nm}^{-2}$   
Ni:  $0.59 \text{ nm}^{-2}$

# APT of Zr sample



At the ridge

Zr

- Protective Ag on top of ridge-GB
- No Ni found
- $\Gamma_{\text{Zr}}: 2.5 \text{ nm}^{-2}$

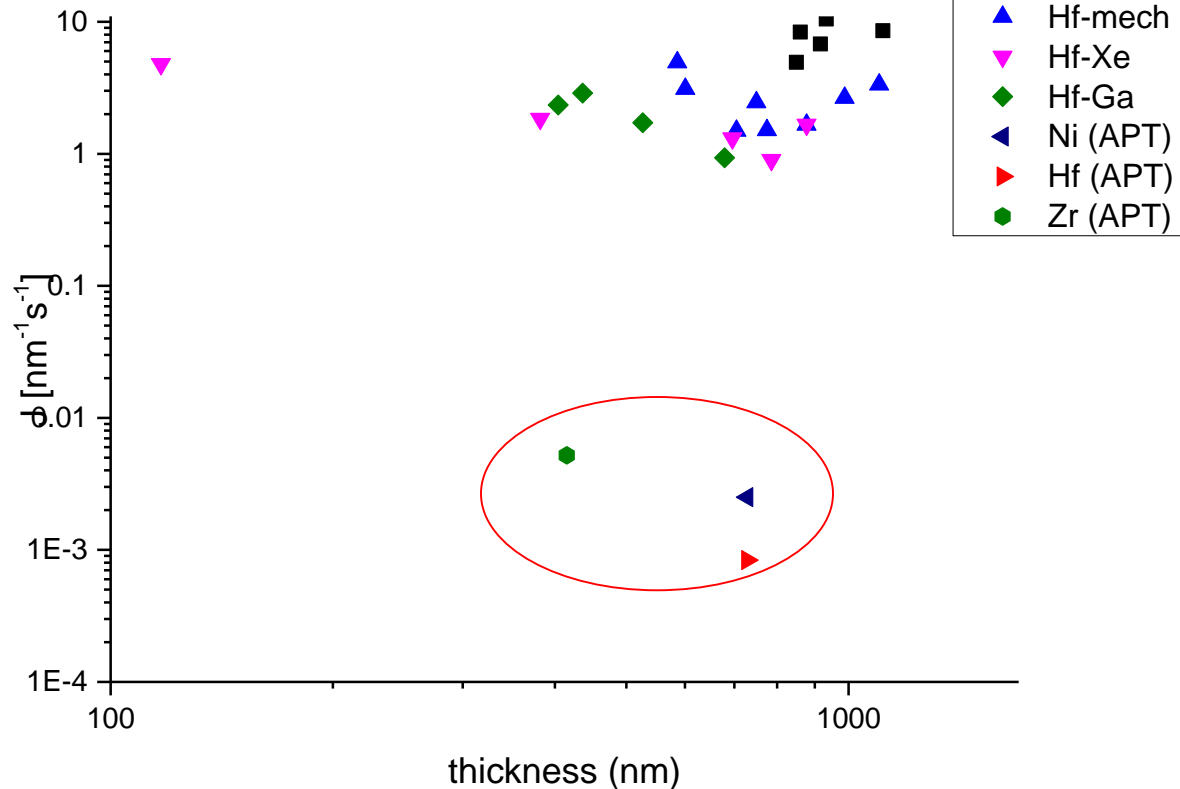
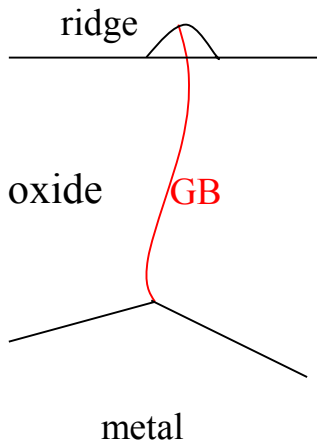


# Outward flux of Ni, Hf, Zr

- Outward flux into ridge GB
- Gibbsian excess
- Additional GB length (ridge height from SEM)

→ amount of diffused material

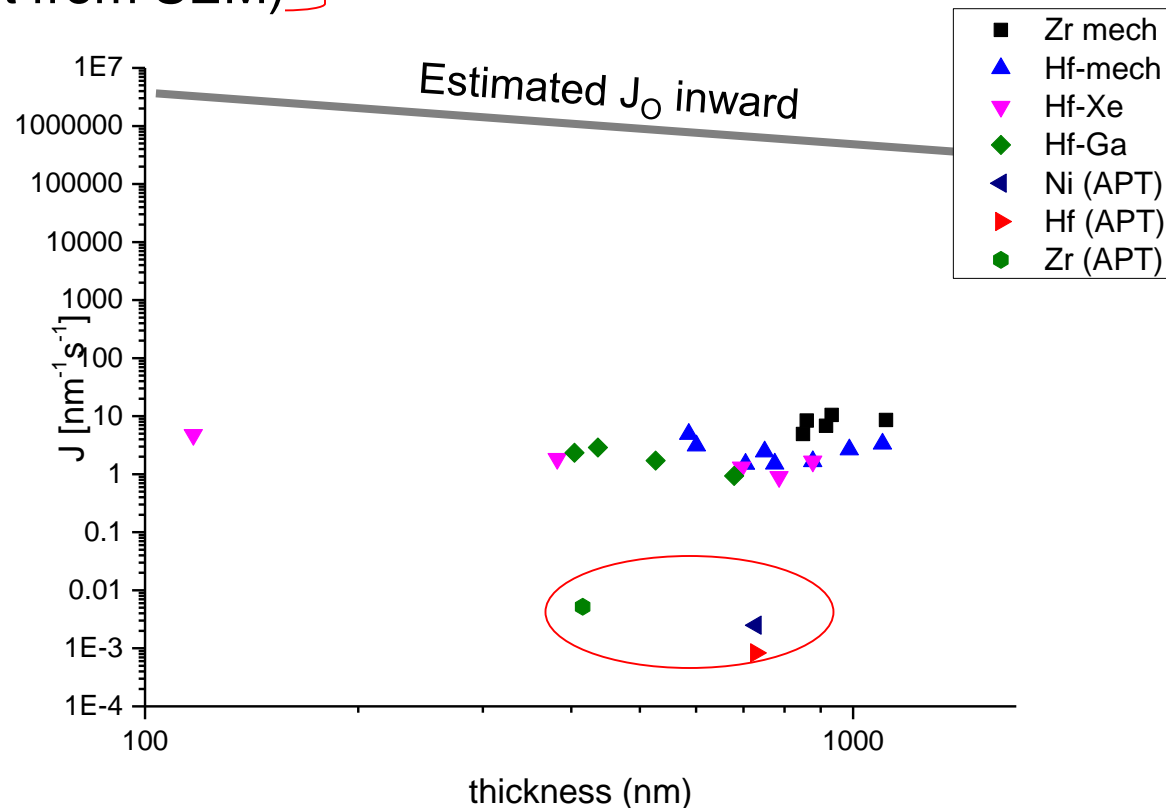
$$J_X = \Gamma_X h_{\text{ridge}}$$



# Outward flux of Ni, Hf, Cr

- Outward flux into ridge GB
- Gibbsian excess
- Additional GB length (ridge height from SEM) } → amount of diffused material
- $J_X = \Gamma_X h_{\text{ridge}}$

$$J_O \gg J_{Al} \gg J_{Hf, Ni, Zr}$$



# Conclusions

- **Outward Diffusion of Al** along  $\text{Al}_2\text{O}_3$  GBs is observed by STEM  
Mechanical polishing introduces defects that promote diffusion  
— Hf reduces Al-outward diffusion stronger than Zr
- Zr is enriched at GBs → **Outward diffusion of Zr, Hf**
- Hf is enriched at GBs
- Ni is found at the GB and at the top of the ridge in the Hf sample → **Outward diffusion of Ni**
- $J_{\text{O}} \sim 10^6 \text{ nm}^{-1}\text{s}^{-1} \gg J_{\text{Al}} \sim 1 \text{ nm}^{-1}\text{s}^{-1} \gg J_{\text{Hf,Ni,Zr}} \sim 10^{-3} \text{ nm}^{-1}\text{s}^{-1}$

# Thank you for your attention

You also want APT results: [knmf.kit.edu](http://knmf.kit.edu), or contact me  
KNMF grants APT time to suitable projects

## Acknowledgements

For help with 2<sup>nd</sup> exposure and sputter coating:  
Patrik Alnegren